

<b>Notice of References Cited</b>	Application/Control No. 10/526,314	Applicant(s)/Patent Under Reexamination HIBINO ET AL.	
	Examiner Tan Ho	Art Unit 2821	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0207565 A1	10-2004	Hibino et al.	343/860
*	B	US-2002/0118075	08-2002	Ohwada et al.	333/32
*	C	US-6,970,140 B2	11-2005	Hibino et al.	343/860
*	D	US-6,765,540 B2	07-2004	Toncich, Stanley S.	343/860
*	E	US-6,201,505 B1	03-2001	Terashima et al.	343/713
*	F	US-5,999,135 A	12-1999	Nozaki et al.	343/713
*	G	US-5,699,071	12-1997	Urakami et al.	343/713
*	H	US-5,239,302 A	08-1993	Maeda et al.	343/704
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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